

ESPEC AMI-U *Ion Migration Evaluation System*



- continuous evaluation of electrochemical migration, insulation deterioration, SIR and CAF test of PCB
- wide range measurement of insulation resistance
- interaction with the ESPEC environmental test chambers
- leak touch detection recognition

Model	AMI - U	AMI – HV - U
Control Channel	Max. 150	Max. 100
Stress Voltage Range	1 to 100V, 1 to 300V & 1 to 500V	50 to 1000V, 50 to 2500V
Resistance Measurement	2×10^5 to 1×10^{13}	1×10^6 to 1×10^{14}
Leak Touch Detection	Less than 100 u sec	10 m sec or greater